

3. (Cancel)

4. (Canceled Previously)

5. (New) A method of accurately determining a resistance of a switch comprising a plurality of parallel-connected transistors, the method comprising:

making contact between the switch and measuring device;

measuring a first resistance of the switch with only a first one of the transistors turned on;

measuring a second resistance of the switch with only a second different one of the transistors turned on;

measuring a third resistance of the switch with both the first transistor and the second transistor turned on; and

using the first, second and third resistances, computing a final resistance of the switch so as to reduce the influence of a contact resistance between the switch and the measuring device.

6. (New) A packaged integrated circuit comprising:

a switch comprising a plurality of parallel-connected transistors, one terminal of the switch being coupled to one pin of the integrated circuit and another terminal of the switch being coupled to another pin of the integrated circuit; and

a control circuit coupled to each of the plurality of transistors to turn each of the plurality of transistors on or off, the control circuit having a test mode;

wherein the control circuit, in said test mode, controls the plurality of transistors such that, in the course of said test mode:

during one period of time only one of the transistors is turned on;

during another different period of time, only a different one of the transistors is turned on; and

during still another period of time, both the one transistor and the different transistor are turned on.

7. (New) A power conversion circuit comprising:

a power supply;

a switch comprising a plurality of parallel-connected transistors, one terminal of the switch being coupled to one pin of the integrated circuit and another terminal of the switch being coupled to another pin of the integrated circuit; and

a control circuit coupled to each of the plurality of transistors to turn each of the plurality of transistors on or off, the control circuit having a test mode;

wherein the control circuit, in said test mode, controls the plurality of transistors such that, in the course of said test mode:

during one period of time only one of the transistors is turned on;

during another different period of time, only a different one of the transistors is turned on; and

during still another period of time, both the one transistor and the different transistor are turned on;

and wherein the power supply is coupled to said one pin.